

TO-220 FULLPAK

Vishay Siliconix

Power MOSFET

PRODUCT SUMMARY				
V _{DS} (V)	800			
$R_{DS(on)}\left(\Omega\right)$	V _{GS} = 10 V	6.5		
Q _g (Max.) (nC)	38			
Q _{gs} (nC)	5.0			
Q _{gd} (nC)	21			
Configuration	Single			

FEATURES

- · Isolated Package
- High Voltage Isolation = 2.5 kV_{RMS} (t = 60 s; f = 60 Hz



RoHS

- Sink to Lead Creepage Distance = 4.8 mm
- · Dynamic dV/dt Rating
- · Low Thermal Resistance
- · Lead (Pb)-free Available

DESCRIPTION

Third generation Power MOSFETs from Vishay provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

The TO-220 FULLPAK eliminates the need for additional insulating hardware in commercial-industrial applications. The molding compound used provides a high isolation capability and a low thermal resistance between the tab and external heatsink. This isolation is equivalent to using a 100 micron mica barrier with standard TO-220 product. The FULLPAK is mounted to a heatsink using a single clip or by a single screw fixing.

ORDERING INFORMATION			
Package	TO-220 FULLPAK		
Lead (Pb)-free	IRFIBE20GPbF		
Lead (Fb)-liee	SiHFIBE20G-E3		
SnPb	IRFIBE20G		
SIFU	SiHFIBE20G		

N-Channel MOSFET

PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			V_{DS}	800	V	
Gate-Source Voltage			V_{GS}	± 20		
Continuous Drain Current	V _{GS} at 10 V	$T_{\rm C} = 25 ^{\circ}{\rm C}$ $T_{\rm C} = 100 ^{\circ}{\rm C}$		1.4	А	
		T _C = 100 °C	I _D	0.86		
Pulsed Drain Current ^a			I _{DM}	5.6		
Linear Derating Factor				0.24	W/°C	
Single Pulse Avalanche Energy ^b			E _{AS}	180	mJ	
Repetitive Avalanche Current ^a			I _{AR}	1.4	Α	
Repetitive Avalanche Energya			E _{AR}	3.0	mJ	
Maximum Power Dissipation	T _C = 25 °C		P_{D}	30	W	
Peak Diode Recovery dV/dtc			dV/dt	2.0	V/ns	
Operating Junction and Storage Temperature Range			T _J , T _{stg}	- 55 to + 150	°C	
Soldering Recommendations (Peak Temperature)) for 10 s 300		300 ^d			
Mounting Torque	6 20 or l	C 00 av M0 aava		10	lbf ⋅ in	
	6-32 or M3 screw			1.1	N · m	

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. $V_{DD} = 50 \text{ V}$, starting $T_J = 25 \text{ °C}$, L = 172 mH, $R_G = 25 \Omega$, $I_{AS} = 1.4 \text{ A}$ (see fig. 12).
- c. $I_{SD} \le 1.8$ A, $dI/dt \le 80$ A/µs, $V_{DD} \le 600$, $T_{J} \le 150$ °C.
- d. 1.6 mm from case.
- * Pb containing terminations are not RoHS compliant, exemptions may apply

IRFIBE20G, SiHFIBE20G

Vishay Siliconix



THERMAL RESISTANCE RATINGS					
PARAMETER	SYMBOL	TYP.	MAX.	UNIT	
Maximum Junction-to-Ambient	R _{thJA}	-	65	°C/W	
Maximum Junction-to-Case (Drain)	R _{thJC}	-	4.1	C/VV	

PARAMETER	SYMBOL	TES	MIN.	TYP.	MAX.	UNIT	
Static						•	
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} =	800	-	-	V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference to 25 °C, I _D = 1 mA		-	0.98	-	V/°C
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_D = 250 \mu A$		2.0	-	4.0	V
Gate-Source Leakage	I _{GSS}	V _{GS} = ± 20 V		-	-	± 100	nA
Zawa Cata Waltana Duain Courset	1	V _{DS} = 800 V, V _{GS} = 0 V		-	-	100	μΑ
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 640 V	V _{DS} = 640 V, V _{GS} = 0 V, T _J = 125 °C		-	500	
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 0.84 A ^b	-	-	6.5	Ω
Forward Transconductance	9 _{fs}	V _{DS} = 10 V, I _D = 0.84 A ^b		1.0	-	-	S
Dynamic		1			l.	•	ı
Input Capacitance	C _{iss}	$V_{GS} = 0 \text{ V},$ $V_{DS} = 25 \text{ V},$ $f = 1.0 \text{ MHz}, \text{ see fig. 5}$		-	530	-	-
Output Capacitance	C _{oss}			-	150	-	
Reverse Transfer Capacitance	C _{rss}			-	90	-	pF
Drain to Sink Capacitance	С			-	12	-	1
Total Gate Charge	Qg		I _D = 1.8 A, V _{DS} = 400 V, see fig. 6 and 13 ^b	-	-	38	nC
Gate-Source Charge	Q _{gs}	V _{GS} = 10 V		-	-	5.0	
Gate-Drain Charge	Q _{gd}	see lig. 6 and 13	-	-	21	1	
Turn-On Delay Time	t _{d(on)}	$V_{DD} = 400 \text{ V}, I_D = 1.8 \text{ A},$ $R_G = 18 \Omega, R_D = 230 \Omega,$ see fig. 10^b		-	8.2	-	ns
Rise Time	t _r			-	17	-	
Turn-Off Delay Time	t _{d(off)}			-	58	-	
Fall Time	t _f			-	27	-	
Internal Drain Inductance	L _D	Between lead, 6 mm (0.25") from package and center of die contact		-	4.5	-	
Internal Source Inductance	L _S			-	7.5	-	- nH
Drain-Source Body Diode Characteristic	s	1			l.	•	ı
Continuous Source-Drain Diode Current	I _S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	1.4	А
Pulsed Diode Forward Current ^a	I _{SM}			i	ı	5.6	
Body Diode Voltage	V_{SD}	$T_J = 25 ^{\circ}\text{C}, \ I_S = 1.4 \text{A}, \ V_{GS} = 0 \text{V}^b$		-	-	1.4	V
Body Diode Reverse Recovery Time	t _{rr}	T _J = 25 °C, I _F = 1.8 A, dl/dt = 100 A/μs ^b		-	380	570	ns
Body Diode Reverse Recovery Charge	Q _{rr}			_	0.94	1.4	μC
Forward Turn-On Time	t _{on}	Intrinsic tu	-on is dominated by L _S and L _D)			_D)	

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. Pulse width \leq 300 μ s; duty cycle \leq 2 %.



TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

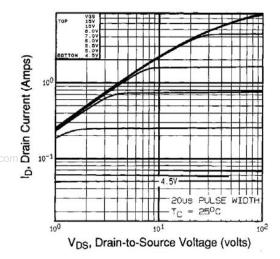


Fig. 1 - Typical Output Characteristics, T_C = 25 °C

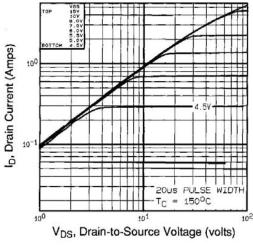


Fig. 2 - Typical Output Characteristics, $T_C = 150$ °C

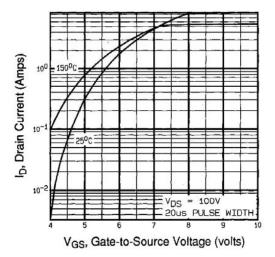


Fig. 3 - Typical Transfer Characteristics

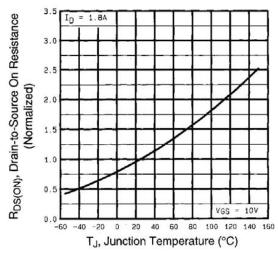


Fig. 4 - Normalized On-Resistance vs. Temperature

IRFIBE20G, SiHFIBE20G

Vishay Siliconix



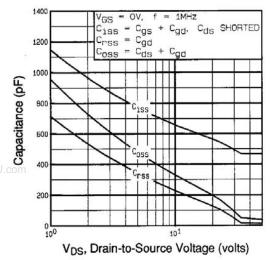


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

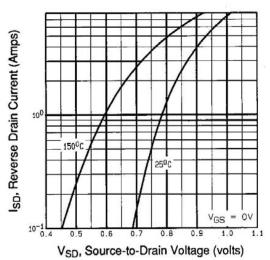


Fig. 7 - Typical Source-Drain Diode Forward Voltage

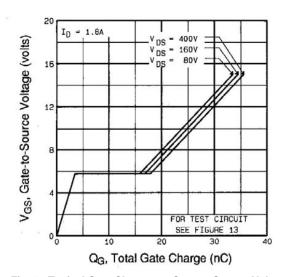


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

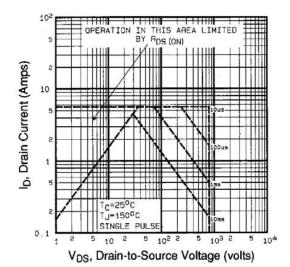


Fig. 8 - Maximum Safe Operating Area



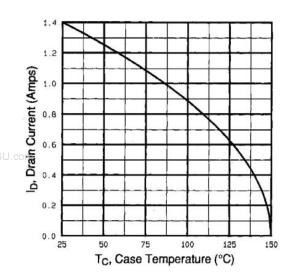


Fig. 9 - Maximum Drain Current vs. Case Temperature

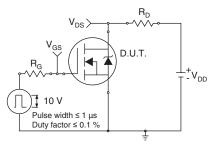


Fig. 10a - Switching Time Test Circuit

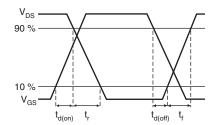


Fig. 10b - Switching Time Waveforms

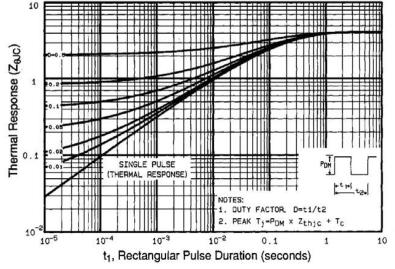


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

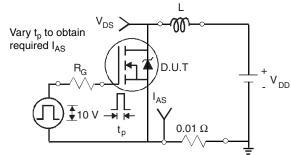


Fig. 12a - Unclamped Inductive Test Circuit

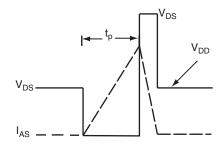


Fig. 12b - Unclamped Inductive Waveforms

Vishay Siliconix



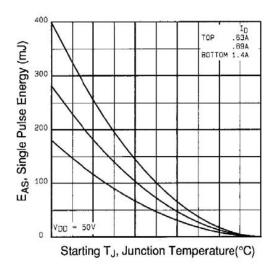


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

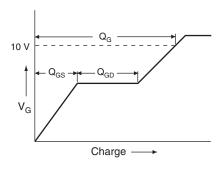


Fig. 13a - Basic Gate Charge Waveform

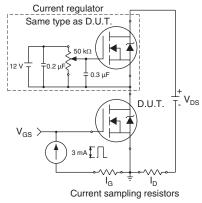
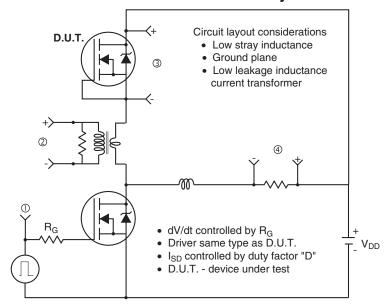


Fig. 13b - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit



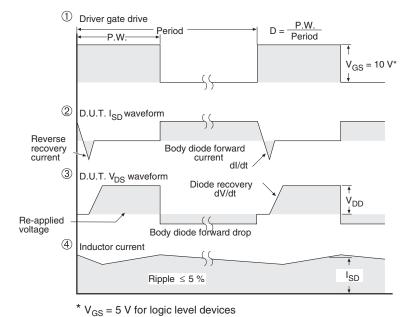


Fig.14 - For N-Channel

Vishay Siliconix maintains worldwide manufacturing capability. Products may be manufactured at one of several qualified locations. Reliability data for Silicon Technology and Package Reliability represent a composite of all qualified locations. For related documents such as package/tape drawings, part marking, and reliability data, see http://www.vishay.com/ppg?91183.

Document Number: 91183 S-81275-Rev. A, 16-Jun-08





Vishay

Disclaimer

All product specifications and data are subject to change without notice.

Vishay Intertechnology, Inc., its affiliates, agents, and employees, and all persons acting on its or their behalf (collectively, "Vishay"), disclaim any and all liability for any errors, inaccuracies or incompleteness contained herein or in any other disclosure relating to any product.

Vishay disclaims any and all liability arising out of the use or application of any product described herein or of any information provided herein to the maximum extent permitted by law. The product specifications do not expand or otherwise modify Vishay's terms and conditions of purchase, including but not limited to the warranty expressed therein, which apply to these products.

No license, express or implied, by estoppel or otherwise, to any intellectual property rights is granted by this document or by any conduct of Vishay.

The products shown herein are not designed for use in medical, life-saving, or life-sustaining applications unless otherwise expressly indicated. Customers using or selling Vishay products not expressly indicated for use in such applications do so entirely at their own risk and agree to fully indemnify Vishay for any damages arising or resulting from such use or sale. Please contact authorized Vishay personnel to obtain written terms and conditions regarding products designed for such applications.

Product names and markings noted herein may be trademarks of their respective owners.

Document Number: 91000 Revision: 18-Jul-08